Lifetime Testing of Laser Diode Arrays

Byron L. Meadows, Farzin Amzajerdian, Bruce W. Barnes, Upendra N. Singh, Michael J. Kavaya
NASA Langley Research Center
Hampton, Virginia, USA

Nathaniel R. Baker
Lockheed Martin Space Operations

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Overview

- Introduction
- Motivation & Requirements
- Issues & Objectives
- Approach & Methodology
- Observations & Results
- Future Work
- Conclusion

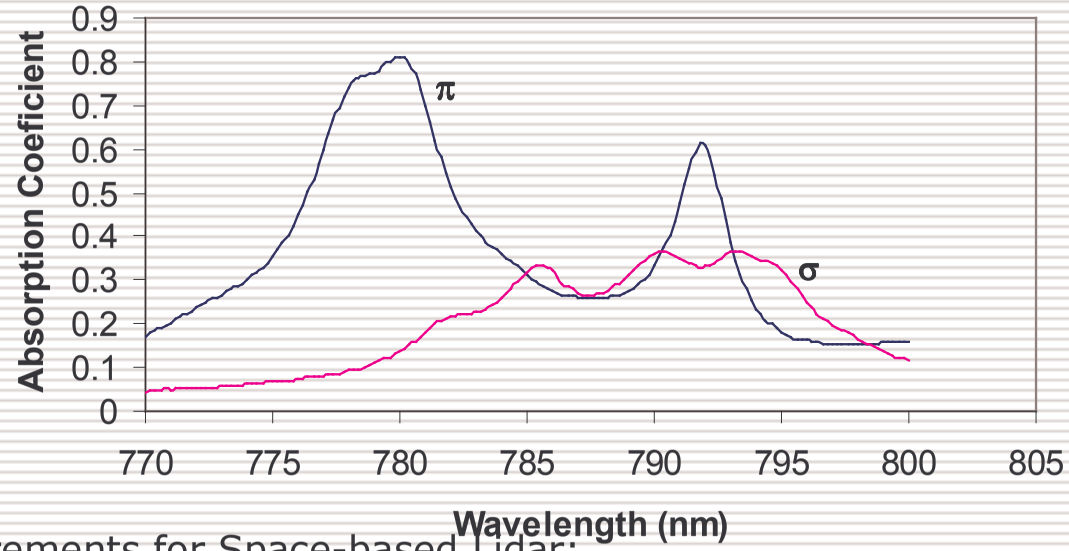
Motivation

Laser Diode Arrays are a critical component of and a major risk area for deploying Lidar instruments in space, defining their efficiency, lifetime, and reliability.

- ***Laser Diode Arrays Establish Instrument Lifetime***

Requirements

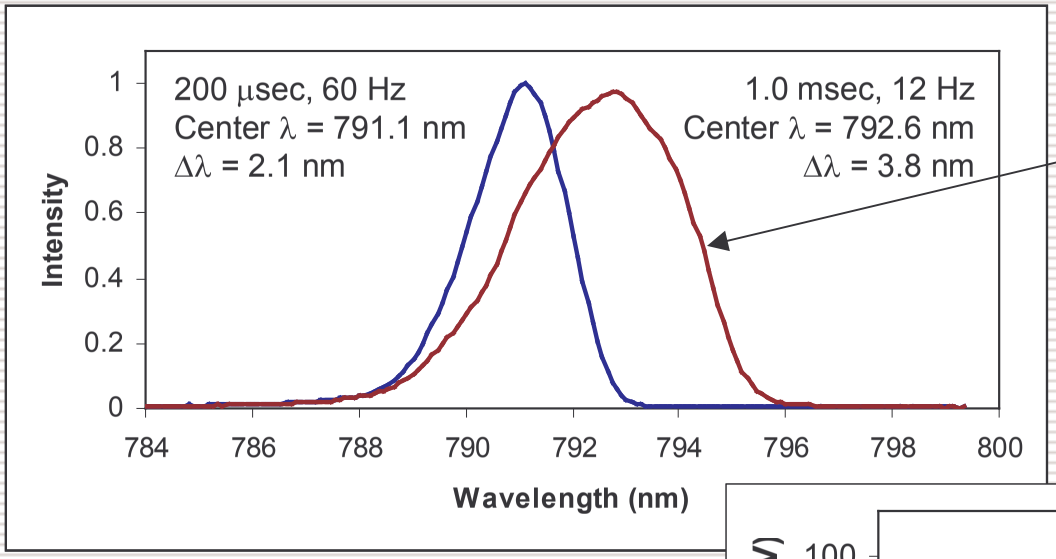
- Moderate and high pulse energy solid state lasers require High Power Quasi-CW 2-D Pump Arrays
  - 808 nm and 200 μsec for 1-micron lasers
  - 792 nm and 1000 μsec for 2-micron lasers



Tm, Ho:YLF Absorption Spectrum

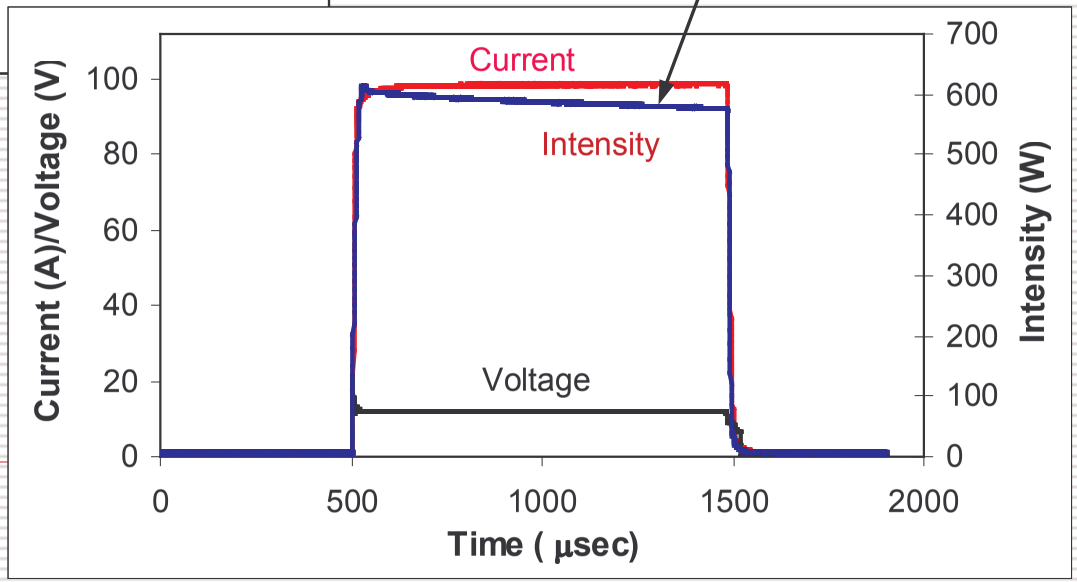
- General Requirements for Space-based Lidar:
  - Conductively-cooled
  - Long lifetime > 3 x 10^9 shots
  - Reliability better than 300 FIT/6-bar device and 1000 FIT/bar
  - Spectral width < 3 nm

Issues



Spectral shift and broadening due to thermal cycling

Intensity drops over 1.0 msec pulse duration due to temperature rise in diode active region



G6-Package
Current 100 A
Op Temp 25°C

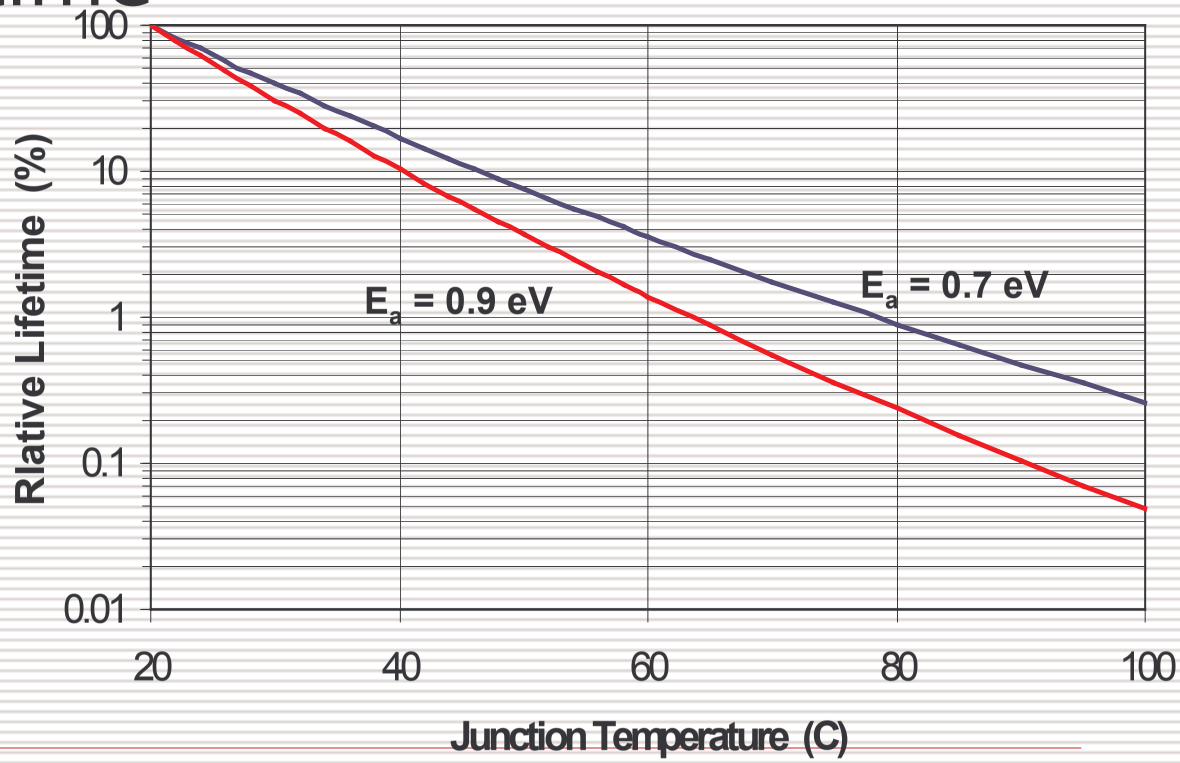
Issues

- Arrhenius indicates a highly reduced relative lifetime

Arrhenius equation:

Lifetime $(\tau) \propto I^{-m} e^{(Ea/kT)}$

T Junction Temperature
I Drive Current
E_a Activation Energy
m Current Acceleration Factor



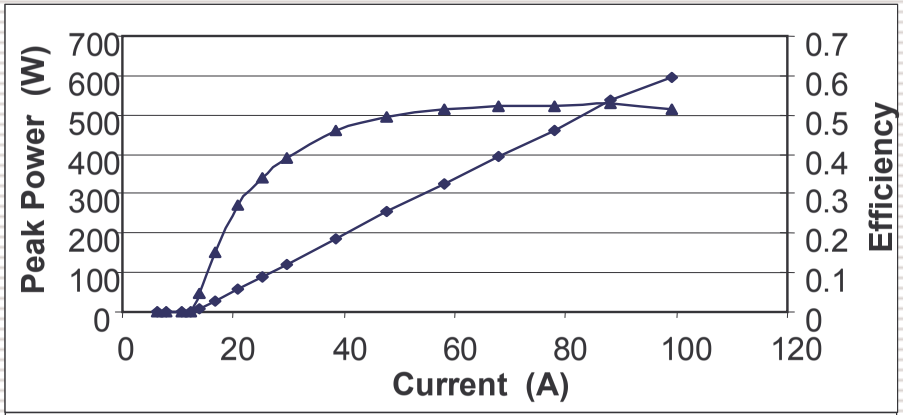
Issues & Objectives

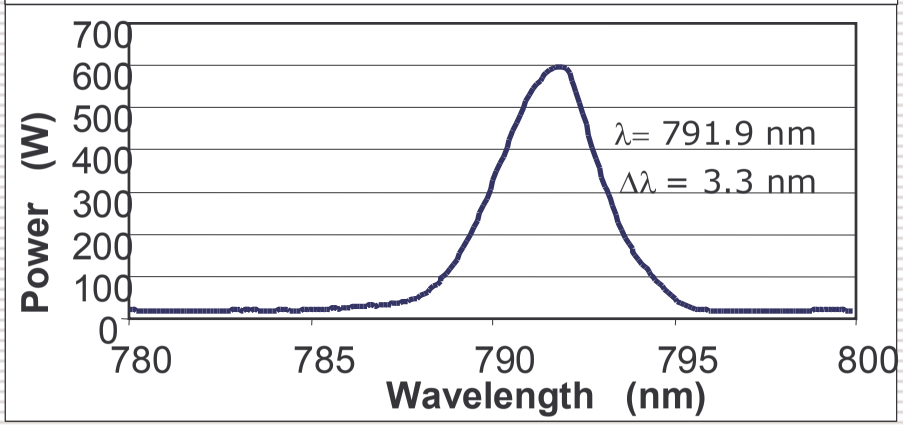
- **Limited reliability and lifetime**
- **Lack of statistical and analytical bases for performance and lifetime prediction**
- **Limited commercial availability**

- **Improve understanding of Laser Diode Arrays**
- **Establish an independent lifetime and performance data base**
- **Investigate development of analytical models for predicting lifetime and performance, enabling end-to-end instrument trade analyses of E, PRF, τ_p, lifetime, …**
- **Support development of advanced Laser Diode Arrays**
- **Provide experimental and analytical results to Laser Diode manufacturers in order to improve fabrication process for higher reliability and consistency**
- **Develop qualification test procedures for space-based lidar instruments**

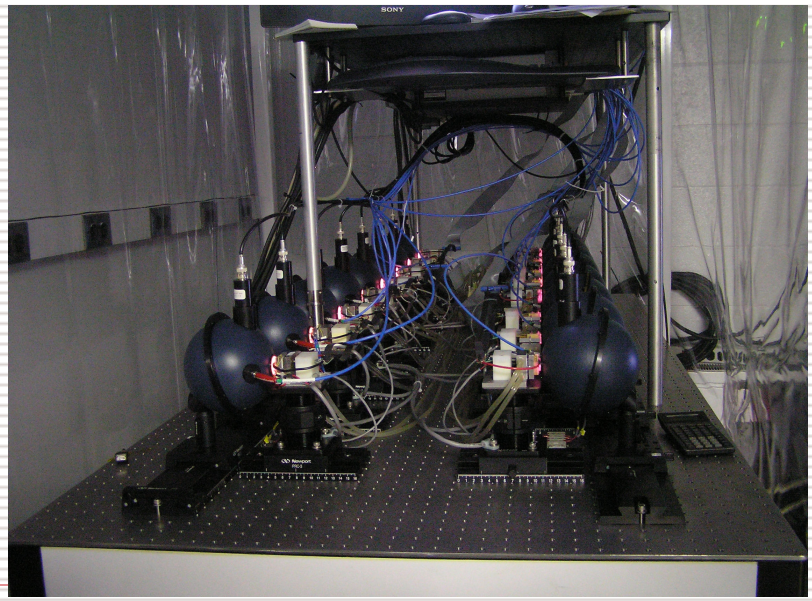
Approach & Methodology

- Characterization:
  - Visual, PIV, λ

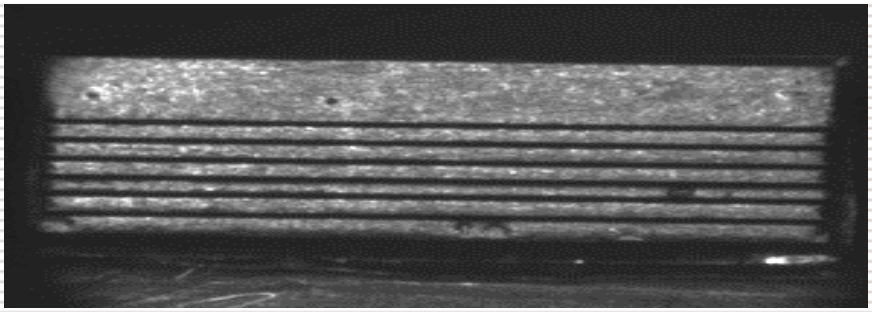


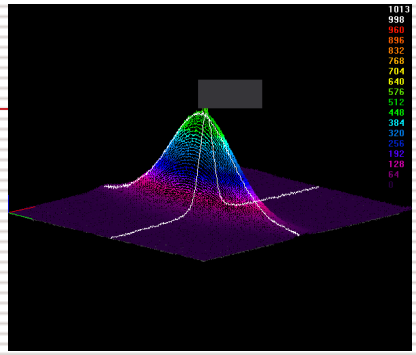


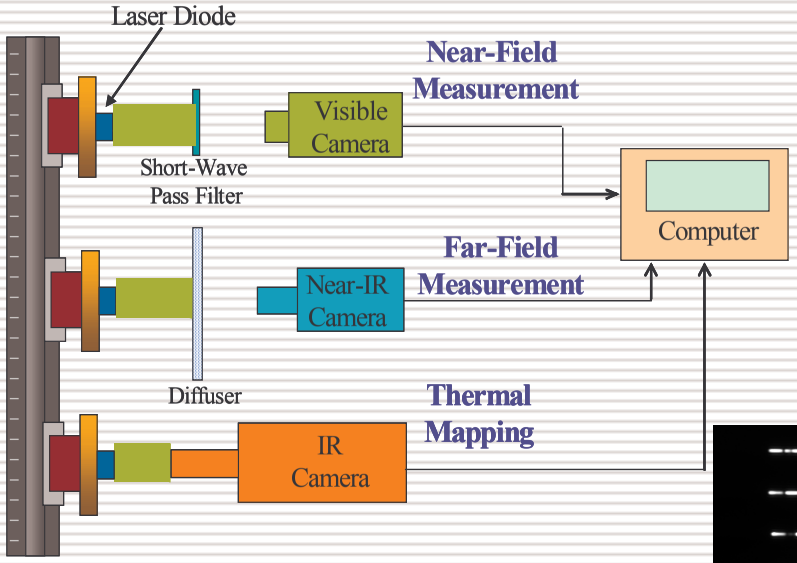
- Lifetesting:
  - 16 LD Arrays Simultaneously
  - 24/7 Fully Automated Control & Operation
  - Data Acquisition and Archive (Performance and all relevant environmental parameters)
  - Diagnosis and Alert
  - PC/Web-based

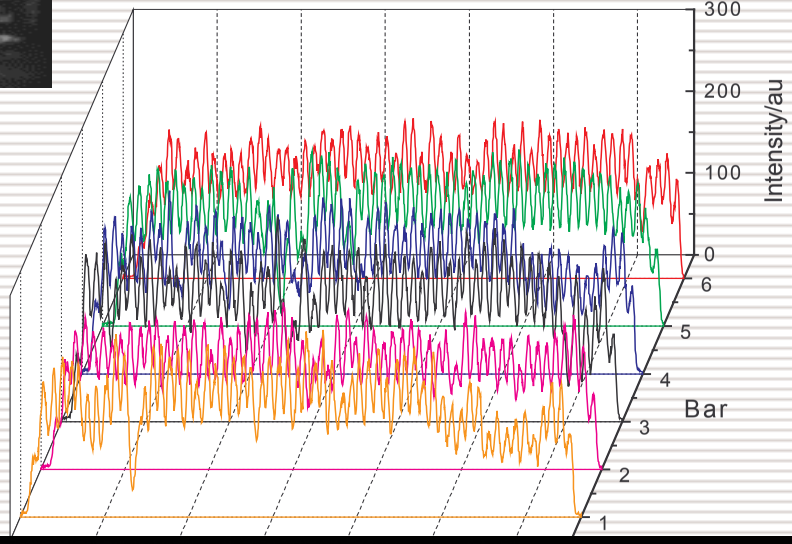


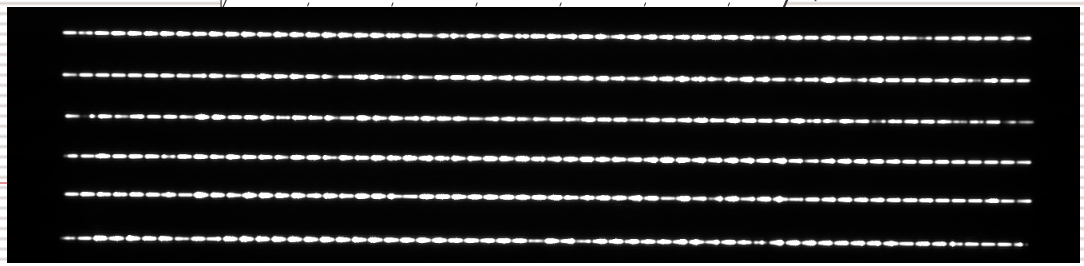
Approach & Methodology



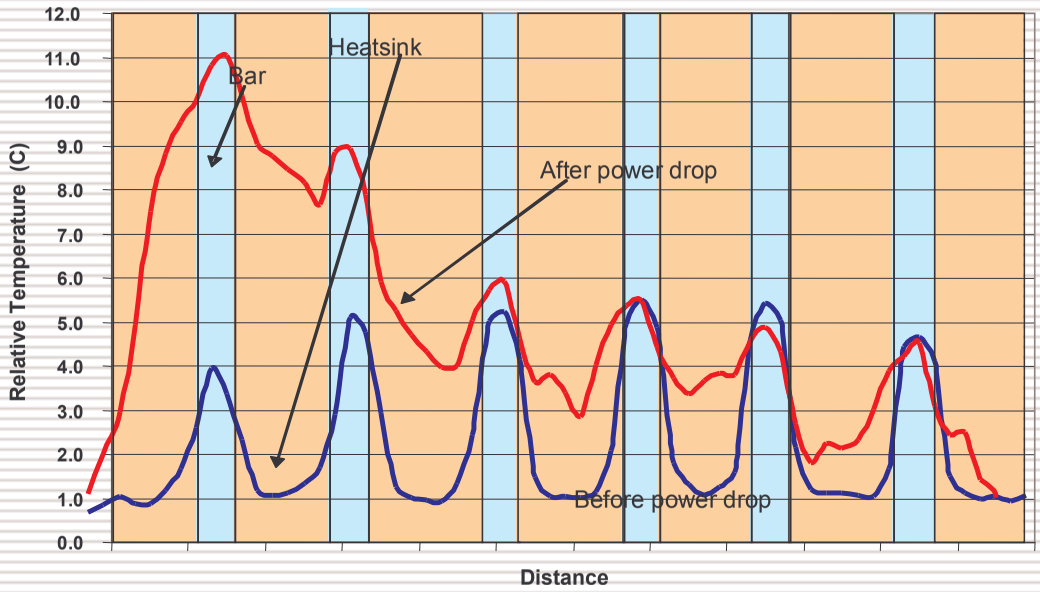


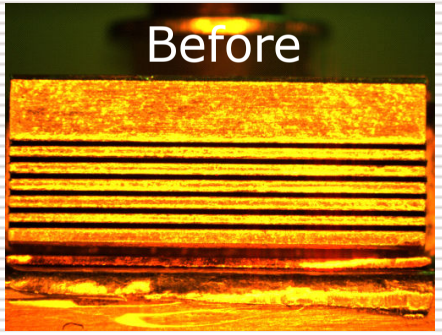


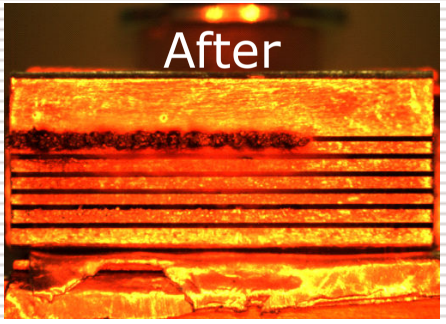


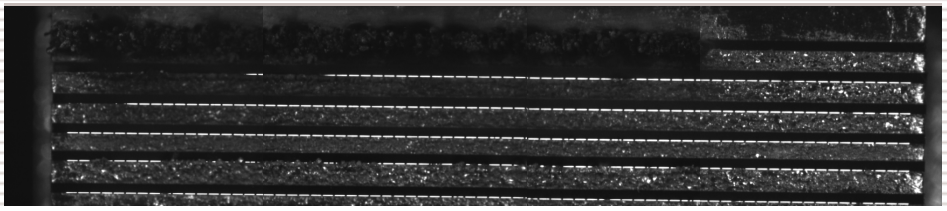


Methodology - IR Analysis









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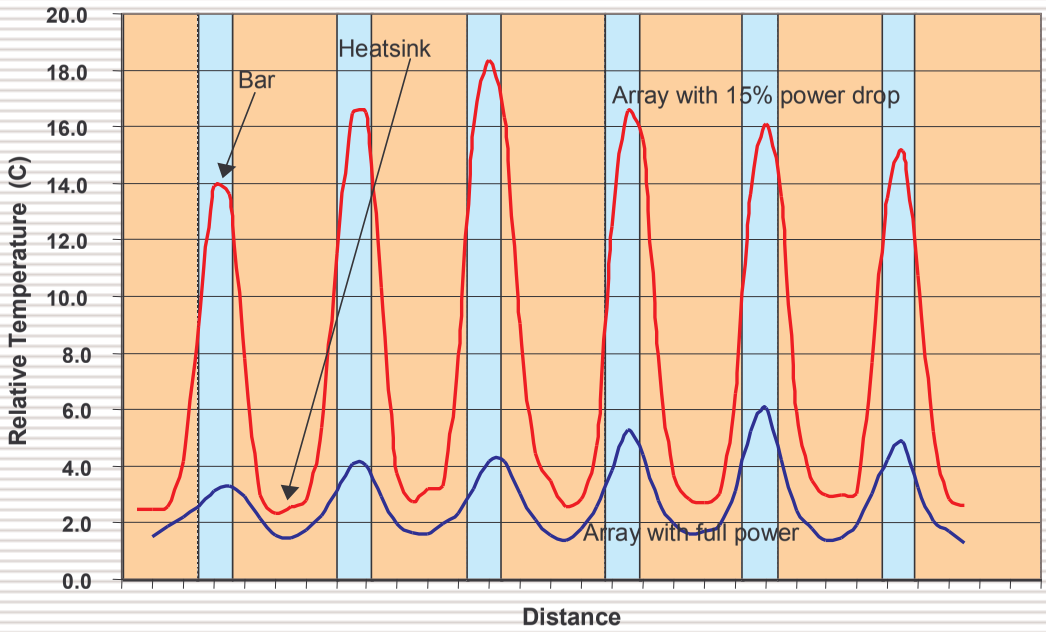
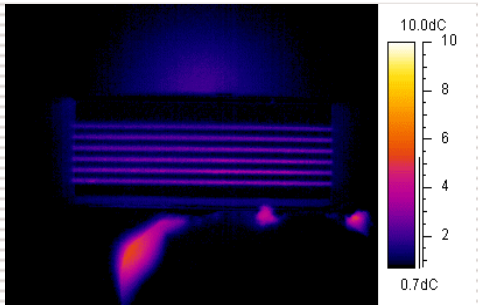
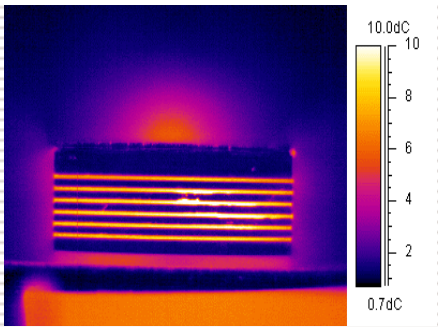


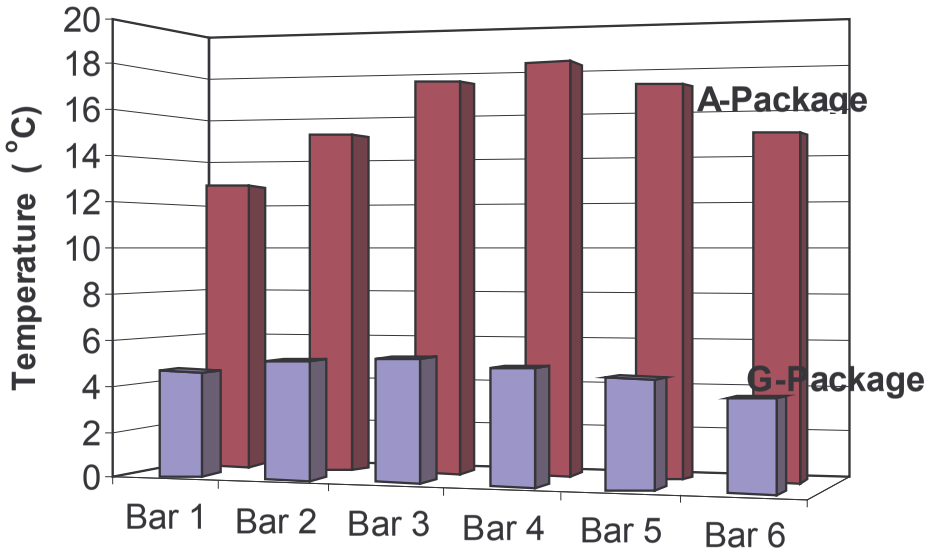
A-6 Array without any dark emitters

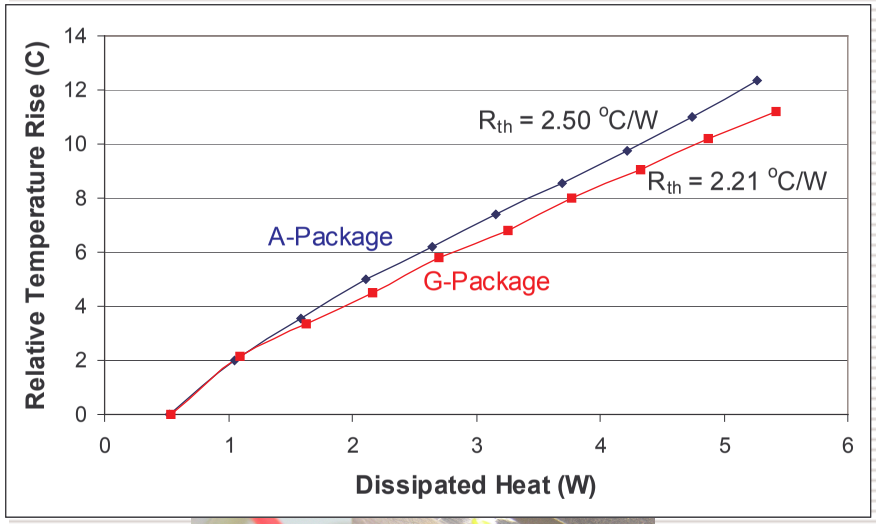


A-6 Array with some failing emitters
(15% drop in power)

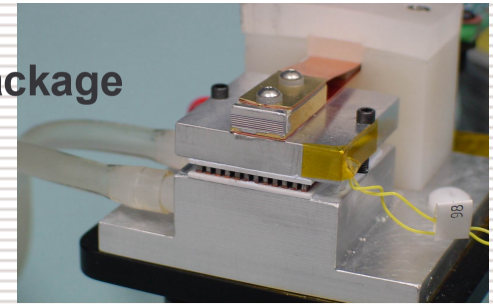


Methodology – IR Analysis

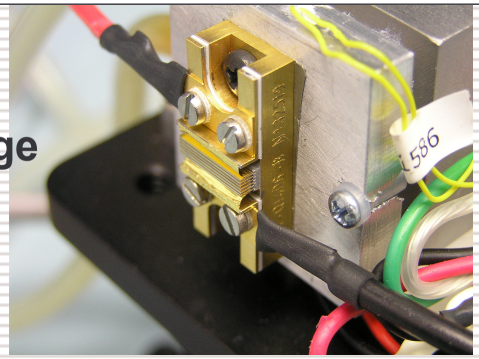




A-package

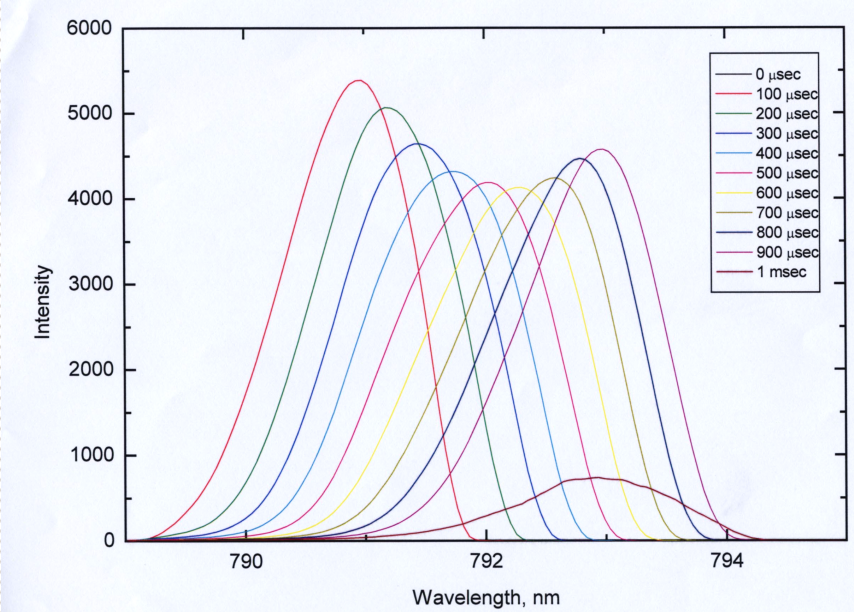


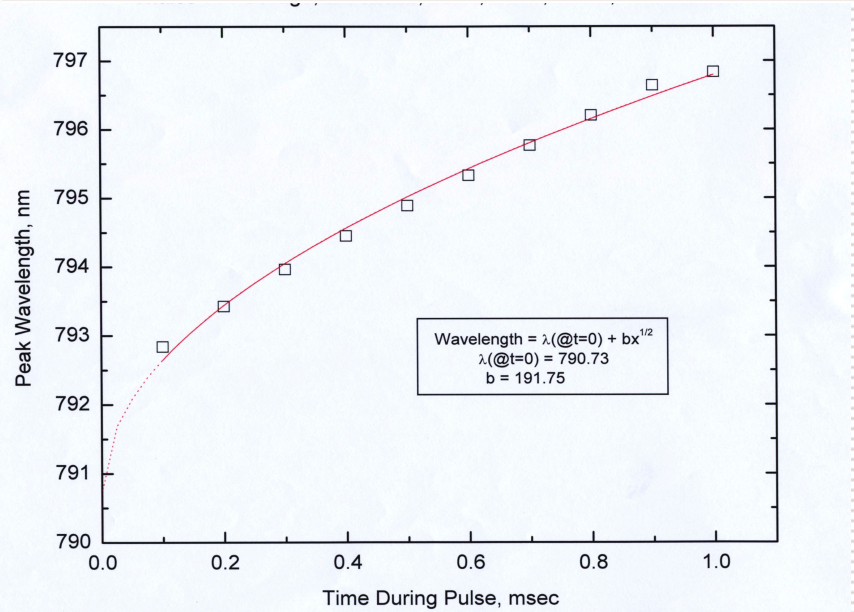
G-package



G-package bars run from 6 to 13 degrees cooler than A-package

Methodology –Temporally Resolved Spectral Measurements



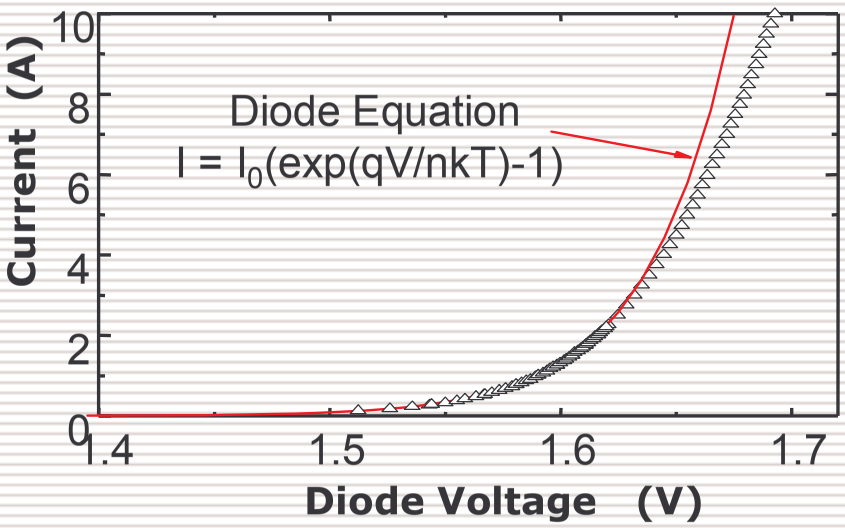


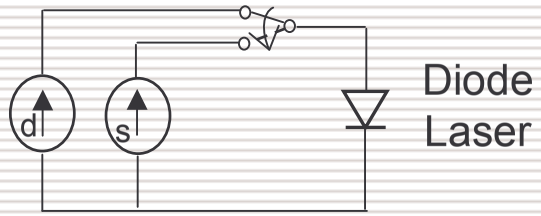
Spectral Shift during Pulse = 6 nm

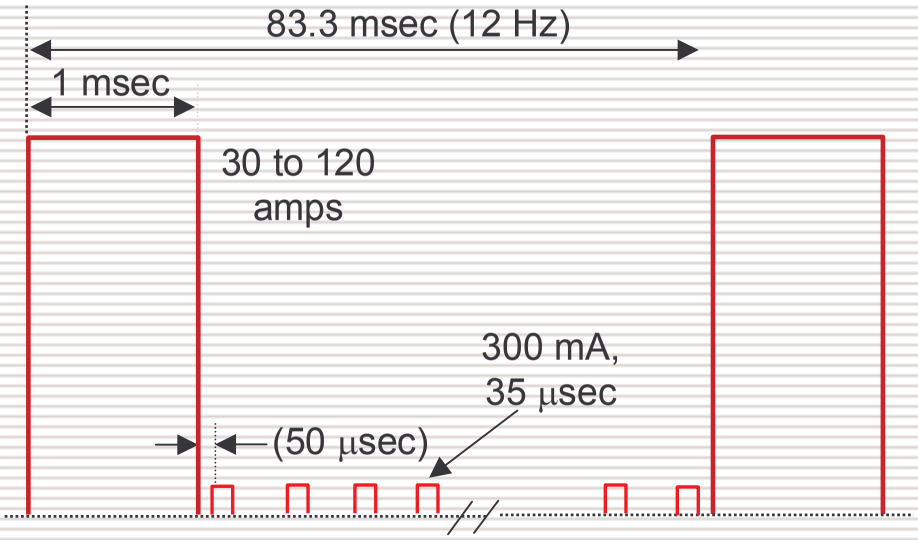
Temperature Rise during Pulse = 6 nm / 0.23 nm/^{o}C = 26 ^{o}C

Methodology – Forward Voltage Short Pulse (Junction Temperature)

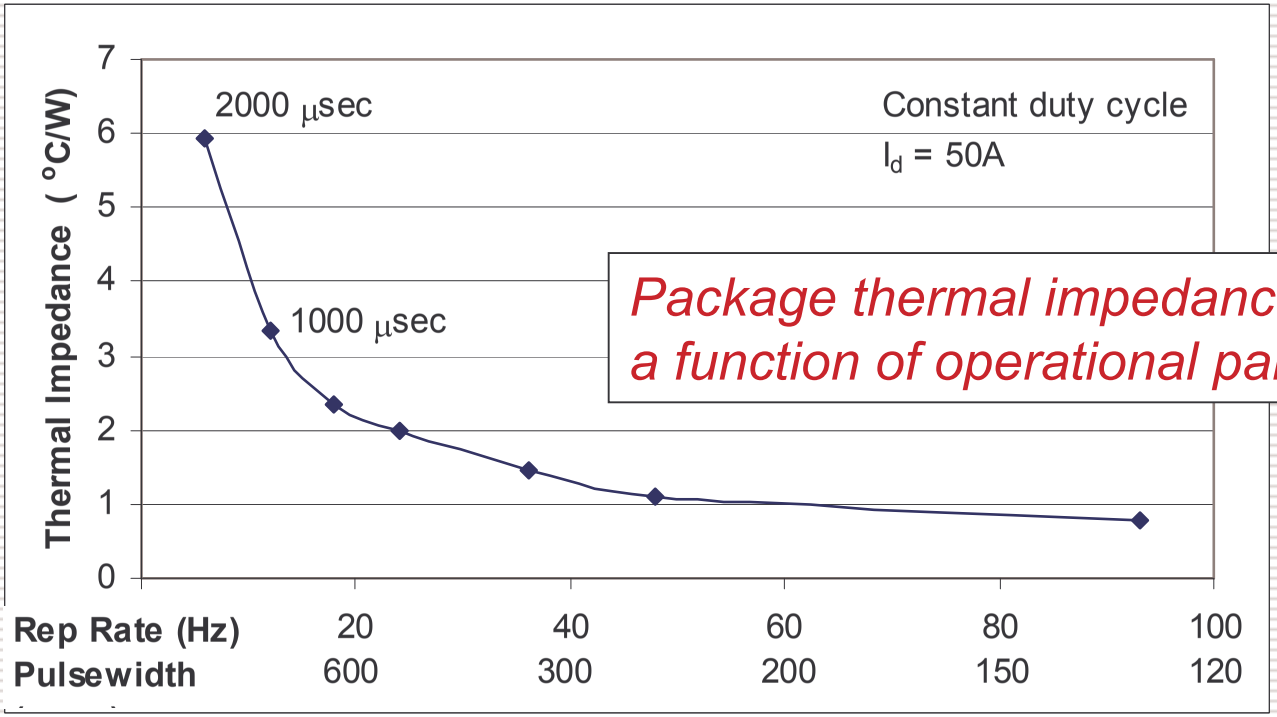
I-V characteristics of LDAs follows classical diode model up to 2.5A







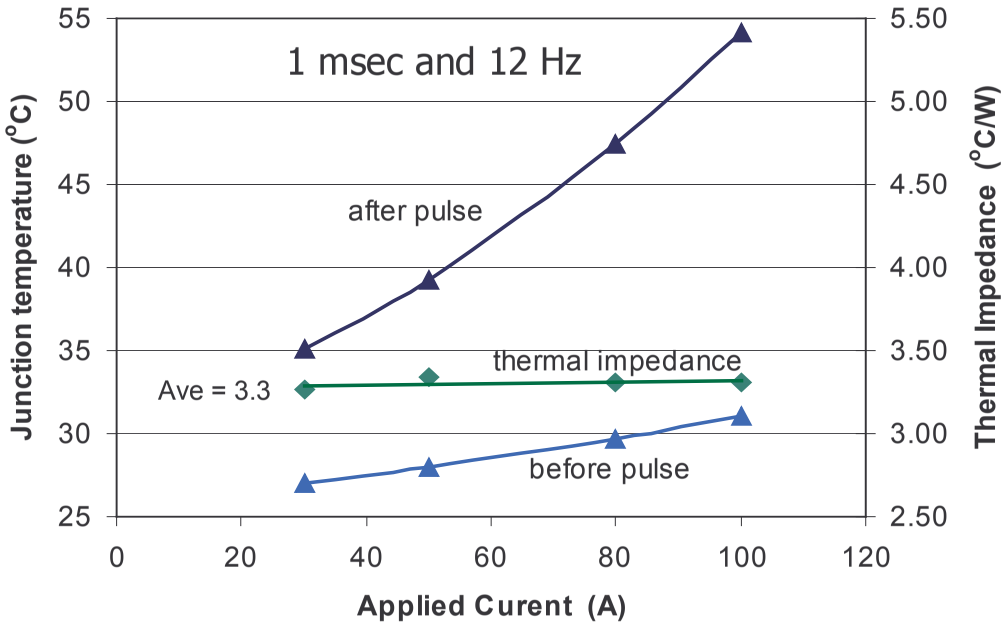
Methodology - FVSP

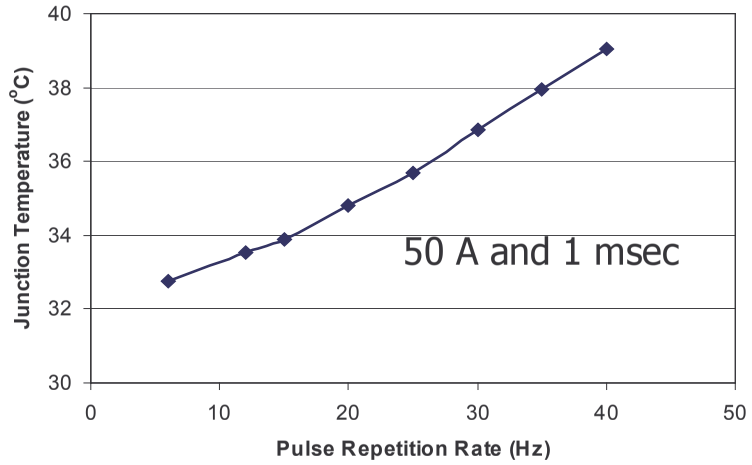


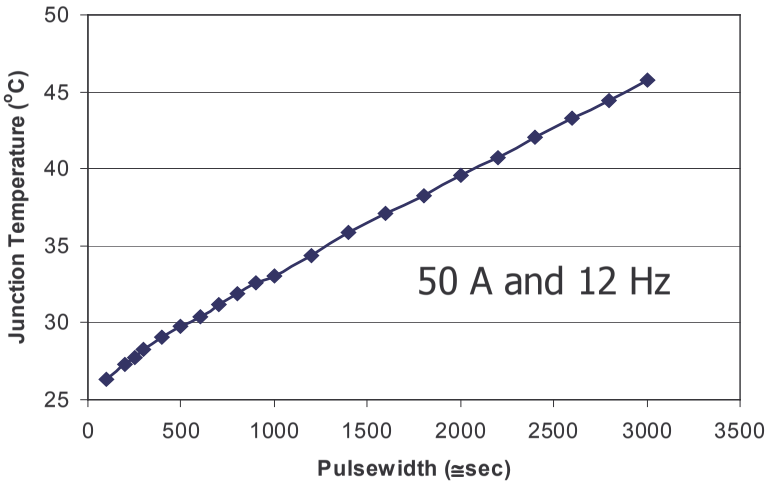
Varying pulsewidth (125 μsec to 2 msec) and repetition rate while keeping duty cycle constant at 1.2%

Average output power = 3.4 W

Methodology - FVSP

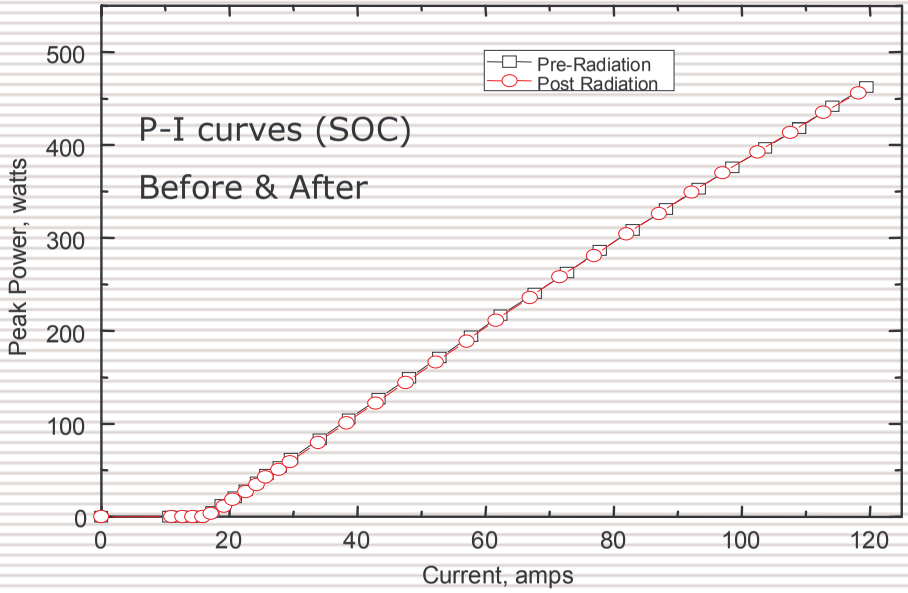


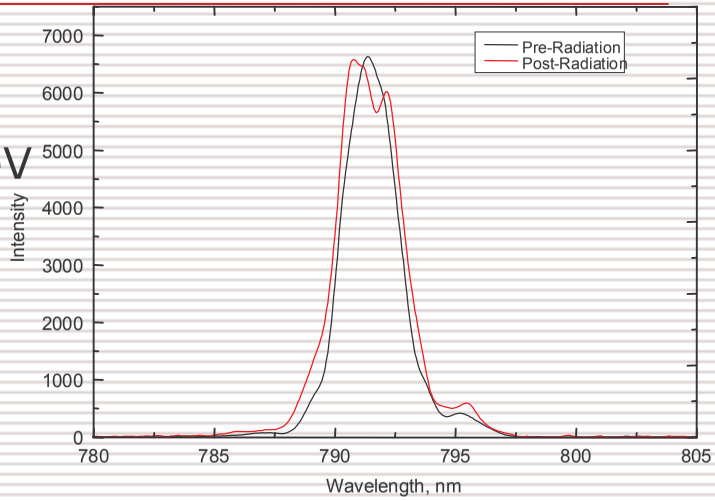


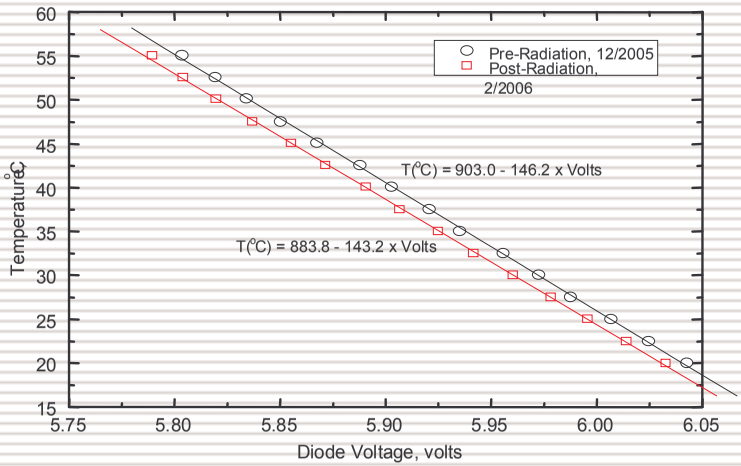


Methodology - Radiation

- Proton radiation testing in collaboration with JHU/APL and GSFC
- LDAs exposed to $2x10^{12}$ p/cm^2 at 200 meV
  - Slight change in junction temperature

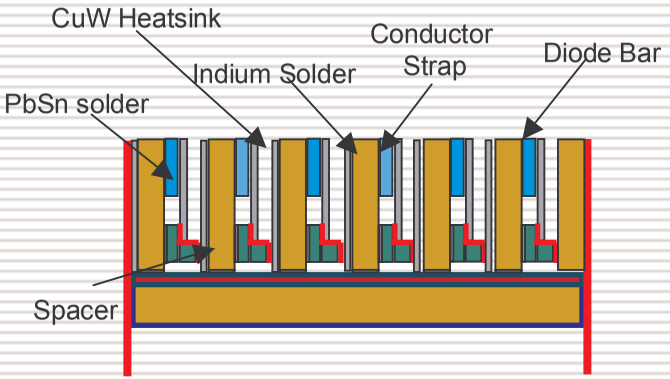




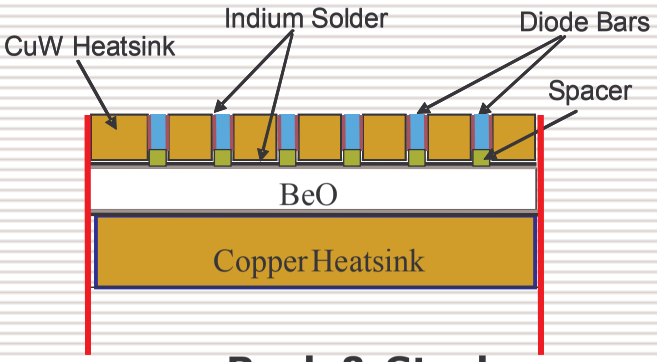


Methodology – Advanced Materials

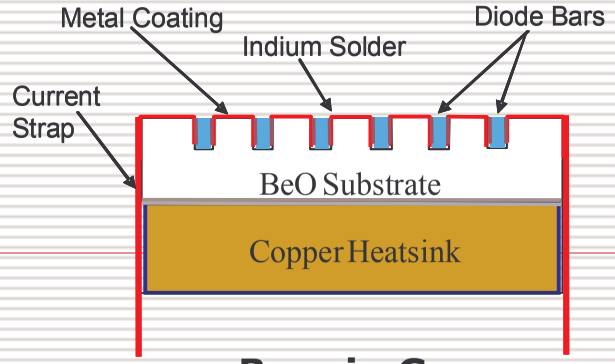
	Material	Coefficient of Thermal Expansion (m/m°C)	Thermal Conductivity (W/m·K)
Standard	GaAs (wafer material)	6.8 x 10^{-6}	46-55
	Indium Solder	29 x 10^{-6}	86
	BeO	8 x 10^{-6}	260
	Copper/CuW	6 - 8 x 10^{-6}	200-250
Advanced	Diamond	1 x 10^{-6}	1100-1600
	Carbon-Carbon Composites	1-6 x 10^{-6}	300-600
	Metal Matrix Composites	6-16 x 10^{-6}	820-890
	AuSn Solder	16	58



Stacked Subassemblies



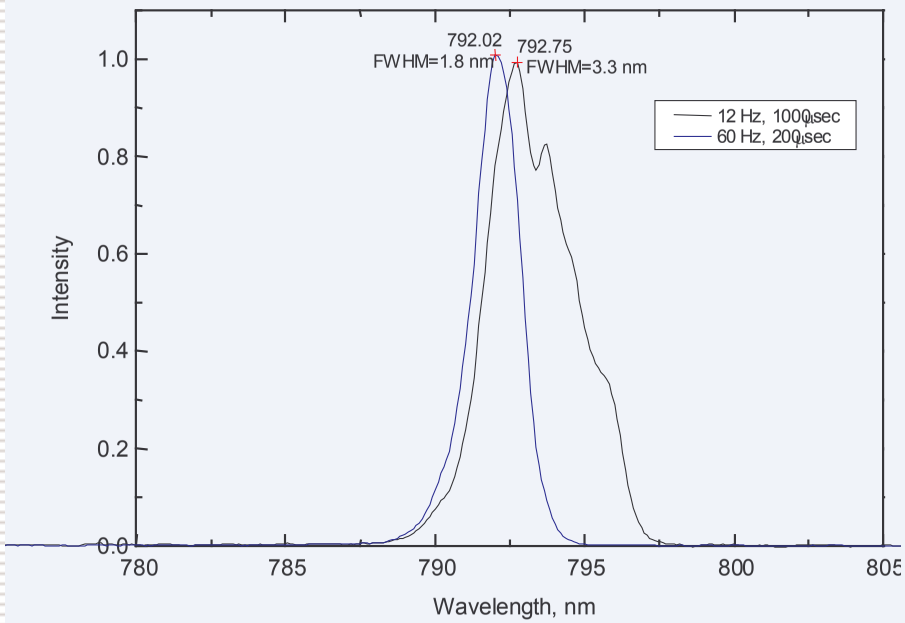
Rack & Stack



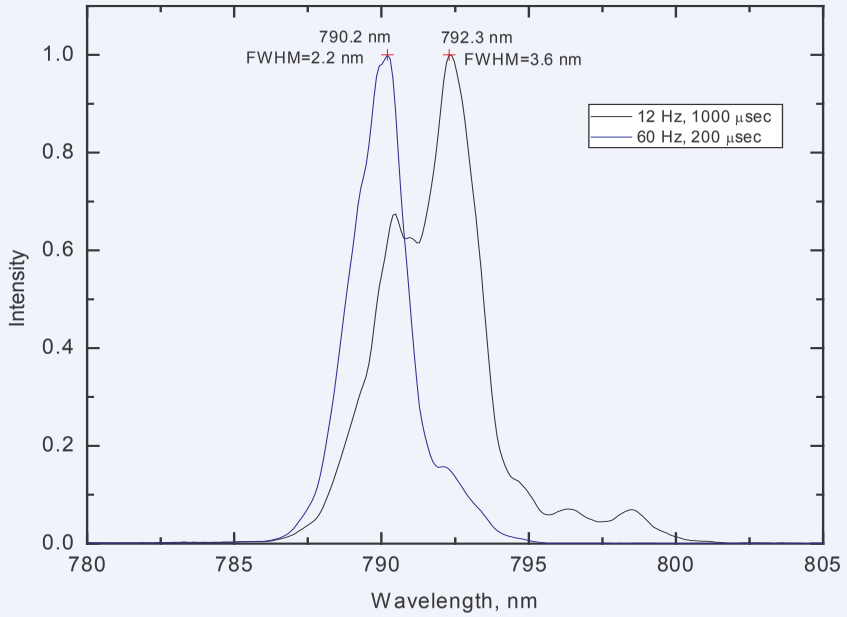
Bars in Groves

Methodology – Advanced Materials

Diamond A-package

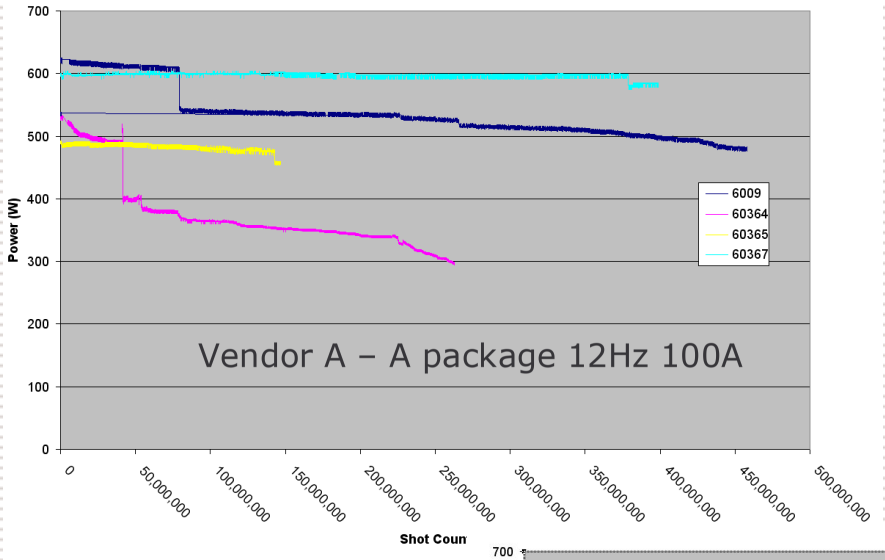


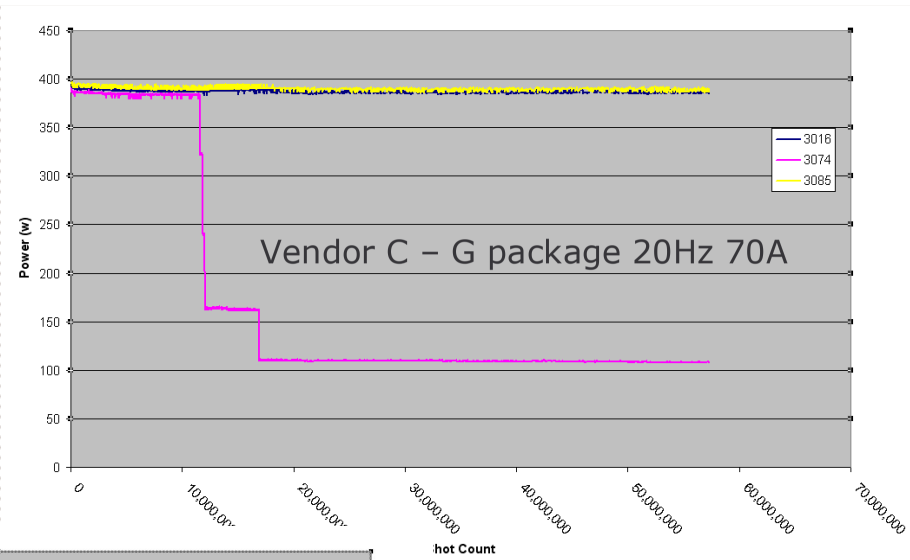
Standard G-package

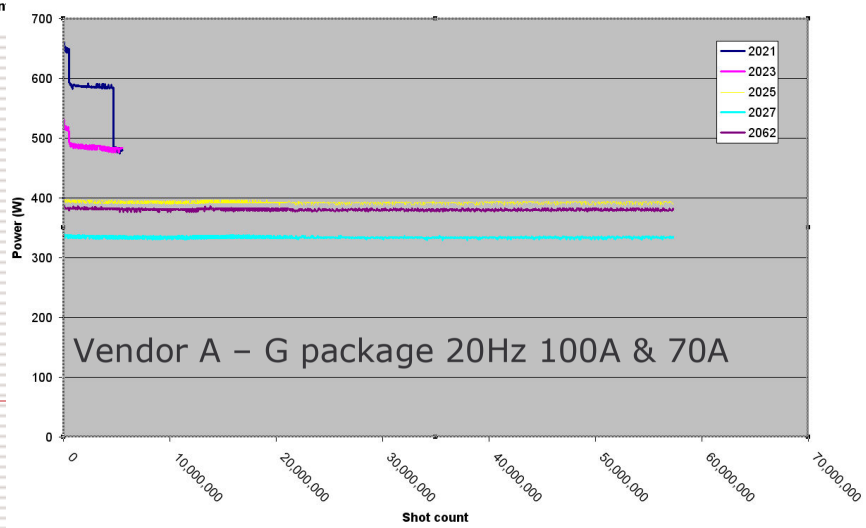


Spectral response at 200 µsec and 1 msec pulse durations

Results – Lifetime







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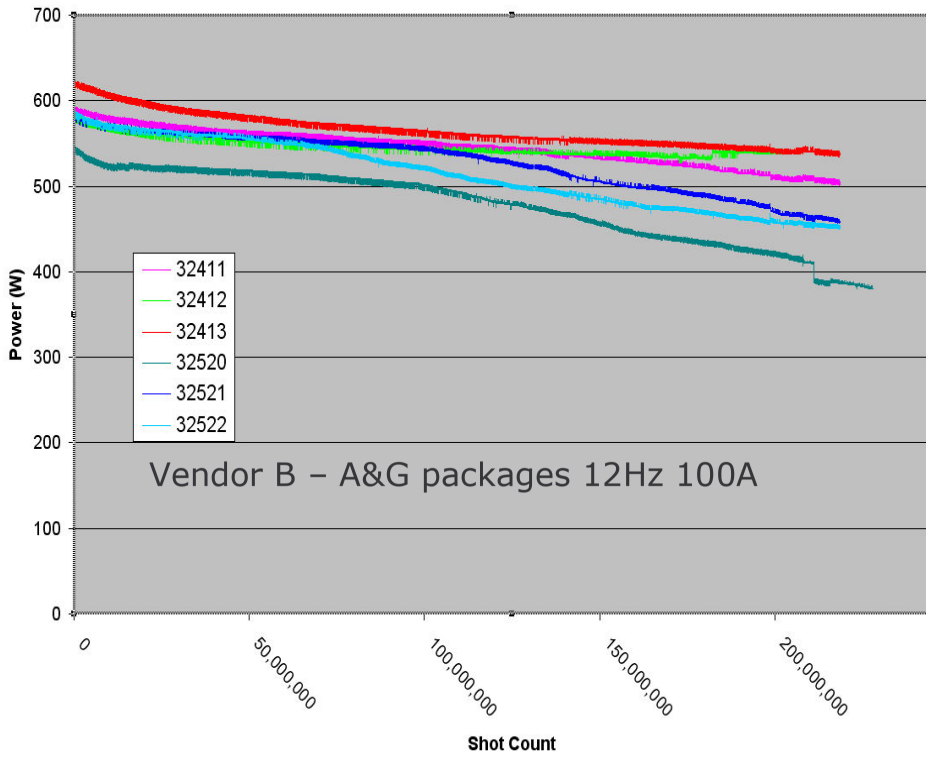

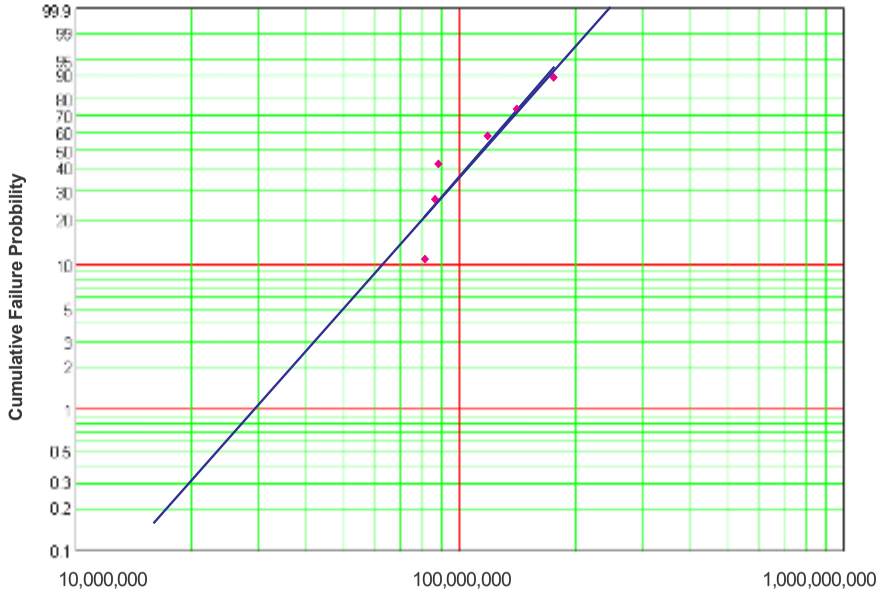

Lessons & Observations

- Trade space
  - Number of bars
  - Bar Pitch
  - Current derating
  - Pulsewidth & prf
  - Temperature
- Screening – FVSP
- Redundant systems

Future Work & Conclusion

- Spectral Mapping – in implementation
- Smart Drivers
- Additional Advanced Materials and Configurations
- Data Processing & Archive
- Continue lifetime testing & re-characterization